# **MOSFET** – Power, Single **N-Channel** 60 V, 2.4 mΩ, 164 A

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- LFPAK8 Package, Industry Standard
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	60	V
Gate-to-Source Voltage	Gate-to-Source Voltage			±20	V
Continuous Drain	Steady State	T <sub>C</sub> = 25°C	I <sub>D</sub>	164	Α
Current R <sub>θJC</sub> (Notes 1, 3)	State	T <sub>C</sub> = 100°C		116	
Power Dissipation		T <sub>C</sub> = 25°C	$P_{D}$	113	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		56	
Continuous Drain	Steady	T <sub>A</sub> = 25°C	I <sub>D</sub>	31	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)	State	T <sub>A</sub> = 100°C		22	
Power Dissipation	]	T <sub>A</sub> = 25°C	$P_{D}$	3.9	W
R <sub>θJA</sub> (Notes 1 & 2)		T <sub>A</sub> = 100°C	l	20	l
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	900	Α
Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>stg</sub>	-55 to + 175	°C	
Source Current (Body Diode)			I <sub>S</sub>	94	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 9 A)		E <sub>AS</sub>	565	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	1.3	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	38	

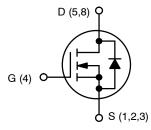
- 1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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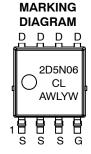
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
60 V	2.4 mΩ @ 10 V	164 A	
	$3.3~\mathrm{m}\Omega$ @ $4.5~\mathrm{V}$	1047	



**N-CHANNEL MOSFET** 



LFPAK8 CASE 760AA



2D5N06CL = Specific Device Code

= Assembly Location

WL = Wafer Lot Υ = Year = Work Week

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information on page 5 of this data sheet.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA		60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				26		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$ ,	T <sub>J</sub> = 25°C			10	μΑ
		V <sub>DS</sub> = 60 V	T <sub>J</sub> = 125°C			250	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 4)					-		
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 135 μA		1.2		2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.0		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		2.0	2.4	mΩ
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 50 A		2.6	3.3	1
Forward Transconductance	9 <sub>F</sub> s	V <sub>DS</sub> =15 V, I <sub>D</sub>	= 50 A		286		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE					•	•
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 25 V			3600		pF
Output Capacitance	Coss				1700		1
Reverse Transfer Capacitance	C <sub>RSS</sub>				28		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 50 A			24		nC
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 50 A			52		1
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 50 A			6.0		1
Gate-to-Source Charge	$Q_GS$				12		1
Gate-to-Drain Charge	$Q_GD$				4.5		1
Plateau Voltage	$V_{GP}$				3.0		V
SWITCHING CHARACTERISTICS (Note 5	5)				•	•	•
Turn-On Delay Time	t <sub>d(ON)</sub>				10		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 48 V,			55		]
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 50 \text{ A}, R_G$	= 2.5 Ω΄		37		1 !
Fall Time	t <sub>f</sub>				8.5		1
DRAIN-SOURCE DIODE CHARACTERIS	TICS					•	•
Forward Diode Voltage	$V_{SD}$	$V_{GS} = 0 \text{ V},$ $T_{J} = 25^{\circ}\text{C}$ $T_{J} = 125^{\circ}\text{C}$			0.8	1.2	V
					0.75		1
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			55		ns
Charge Time	t <sub>a</sub>				28		1
Discharge Time	t <sub>b</sub>				28		1
Reverse Recovery Charge	$Q_RR$				60		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
4. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

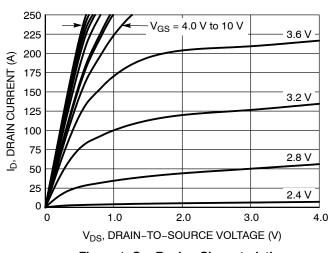


Figure 1. On-Region Characteristics

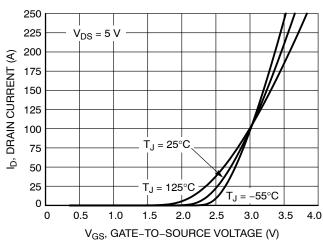


Figure 2. Transfer Characteristics

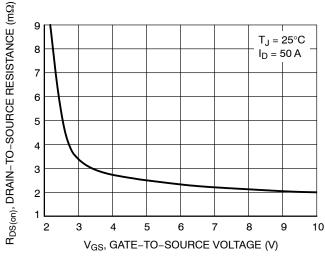


Figure 3. On-Resistance vs. Gate-to-Source Voltage

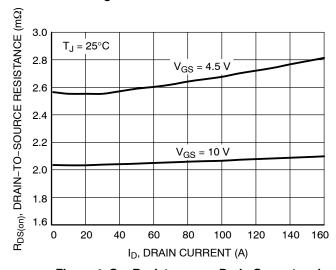


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

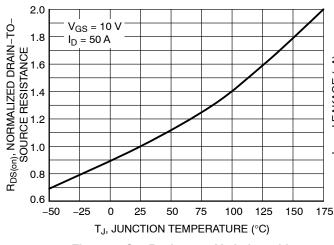


Figure 5. On–Resistance Variation with Temperature

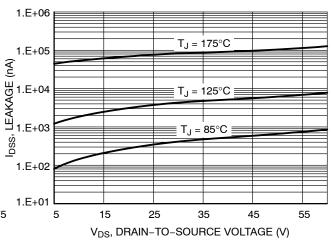


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

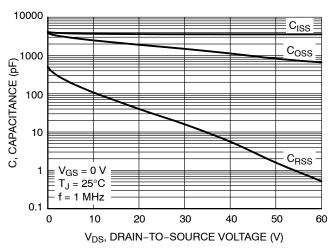


Figure 7. Capacitance Variation

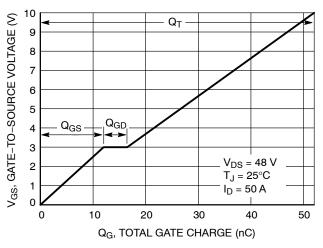


Figure 8. Gate-to-Source vs. Total Charge

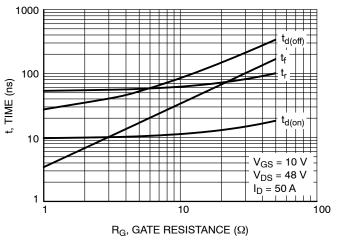


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

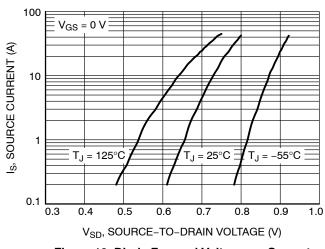


Figure 10. Diode Forward Voltage vs. Current

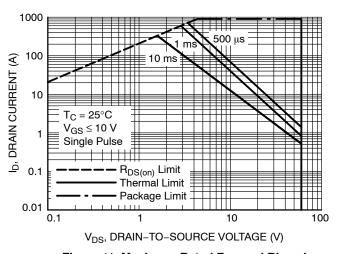


Figure 11. Maximum Rated Forward Biased Safe Operating Area

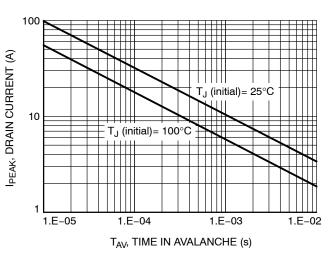


Figure 12. Maximum Drain Current vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

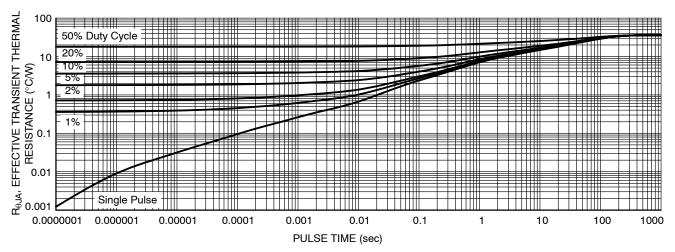


Figure 13. Thermal Characteristics

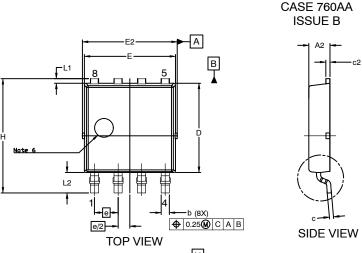
#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVMJS2D5N06CLTWG	2D5N06CL	LFPAK8 (Pb-Free)	3000 / Tape & Reel

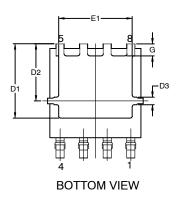
<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

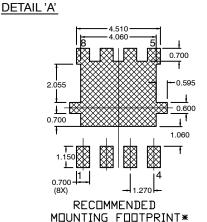
#### PACKAGE DIMENSIONS

LFPAK8 5x6



# Н 0.10 C





For additional information on our Pb-Free strategy and soldering details, please download the DN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D.

#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.
- OPTIONAL MOLD FEATURE.

MILLIMETERS					
DIM	MIN	NOM	MAX		
Α	1.10	1.20	1.30		
A1	0.00	0.08	0.15		
A2	1.10	1.15	1.20		
АЗ	(	).25 REF			
A4	0.45	0.50	0.55		
р	0.40	0.45	0.50		
С	0.19	0.22	0.25		
c2	0.19	0.22	0.25		
D	4.70	4.80	4.90		
D1	_	_	4.20		
D2	3.00	3.10	3.20		
D3	0.30	0.40	0.50		
П	4.80	4.90	5.00		
E1	3.90	4.00	4.10		
E2	5.00	5.15	5.30		
Ф	1.27 BSC				
G	0.55	0.65	0.75		
Н	6.00	6.15	6.30		
Г	0.40	0.65	0.85		
L1	0.15	0.25	0.35		
L2	0.80	1.05	1.30		
q	0°	4°	8°		

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